IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

No.: 10/689,314

Applicant

: David Berman et al.

Filed

: October 20, 2003

Title

: X-RAY REFLECTOMETRY OF THIN FILM LAYERS

WITH ENHANCED ACCURACY

Art Unit

: 2882

Docket No.

: 22350/21

Customer No.

: 1912

STATEMENT OF LACK OF DECEPTIVE INTENTION

I was mistakenly omitted as a co-inventor with David Berman and Alex Dikopoltsev on the above-identified patent application, and the error in inventorship occurred without deceptive intention on my part.

Dated: 20th oct, 2005

Dileep Agnihotri